



4/17/2012

**RELIABILITY MONITOR REPORT  
FOR**

**San Antonio 0.8 $\mu$ m Silicon Gate CMOS EEPROM (EB8)**

**MAXIM Integrated Products**

120 San Gabriel Dr.  
Sunnyvale, CA 94086

**This Report was prepared by  
Maxim Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX1781ETM+
-------------

The calculated failure rate for devices using this process is:

**FAILURE RATE: MTTF (YRS): 8720      QUANTITY: 45      FAILS: 0      FITS: 13.1**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%      Ea: 0.7      Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2011 and 3/31/2012 .

**Process Information:**

Process Description: San Antonio 0.8µm Silicon Gate CMOS EEPROM (EB8)

**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1132	MAX1781ETM+	135C	1000 HRS	45	0	TML5AA1Z1Q2
<b>Total:</b>						<b>0</b>	

**STORAGE LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1132	MAX1781ETM+	150C	1000 HRS	77	1	TML5AA1Z1Q2
<b>Total:</b>						<b>1</b>	

**TEMPERATURE CYCLE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1132	MAX1781ETM+	-65C TO 150C	1000 CYS	76	0	TML5AA1Z1Q2
TEMP CYCLE, 5' RAMP, 10' DWELL	1132	MAX1781ETM+	-65C TO 150C	1000 CYS	77	1	TML5AA1Z1Q3
<b>Total:</b>						<b>1</b>	

**TEMPERATURE HUMIDITY BIAS**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
BIASED MOISTURE	1132	MAX1781ETM+	130C, 85% R.H.	500 HRS	30	1	TML5AA1Z1Q3
<b>Total:</b>						<b>1</b>	

**FAILURE RATE: MTTF (YRS): 8720      QUANTITY: 45      FAILS: 0      FITS: 13.1**